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# Anomaly Detection Based on Semi-Formula Driven Pre-training Dataset to Represent Subtle Difference and Anomaly Score

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### 1. Task

Normal/Anomaly classification
 No anomaly images for training



- 2. Related Works (PaDiM<sup>[1]</sup>)
- Training with only normal images
- Using pre-training model



- 3. Problem of ImageNet<sup>[2]</sup>
- 1. No separation of subtle difference





2. No relative relationship of label



Pre-trained parameters

Is ImageNet really the best choice?

# - 4. Basic Idea and Proposed Method

Basic idea

Representing subtle difference and anomaly score



# ImageNet has (a) No separation of subtle difference (b) No relative relationship of label => It will make poor feature space

Proposed idea has
(a) Separation of subtle difference
(b) Relative relationship of label
 based on anomaly score
=> It will make good feature space

## 5. Experiments

- 1. Proposed semi-formula driven dataset with BTAD<sup>[3]</sup>
  - 1. Examples of generated anomaly images (18 out of 1,000,000 images)



2. Results of changing each parameter E.g., y-standard deviation indicates vertical size



2. Anomaly detection performance (4 categories of MVTec AD<sup>[4]</sup>)

#### Proposed method

1. Create large-scale dataset

Random GMM parameter is added to 1-normal image, and 1-anomaly image is generated.



Pre-train with large-scale dataset
 CNN is pre-trained by minimizing of each loss.



![](_page_0_Figure_40.jpeg)

#### Proposed method can detect defects with high precision.

![](_page_0_Picture_42.jpeg)

Pre-training to represent subtle difference and anomaly score
 Characteristic
 Pre-trained feature space represents
 Subtle difference
 Anomaly score
 Result
 High performance for categories where ImageNet performed poorly.

#### <Reference>

[1] T. Defard, et al., PaDiM: A Patch Distribution Modeling Framework for Anomaly Detection and Localization, ICPR, 2021.
 [2] J. Deng, et al., ImageNet: A Large-Scale Hierarchical Image Database, CVPR, 2009.

[3] P. Mishra, et al., VT-ADL: A Vision Transformer Network for Image Anomaly Detection and Localization, ISIE, 2021.

[4] P. Bergmann, et al., The MVTec Anomaly Detection Dataset: A Comprehensive Real-World Dataset for Unsupervised Anomaly Detection, IJCV, 2021.
[5] H. Kataoka, et al., Pre-Training Without Natural Images, IJCV, 2022.
[6] M. Wieler and T. Hahn, Weakly Supervised Learning for Industrial Optical Inspection, DAGM, 2007.

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